

BLF8G27LS-100V

Power LDMOS transistor

Rev. 3 — 29 January 2013

Product data sheet

1. Product profile

1.1 General description

100 W LDMOS power transistor with improved video bandwidth for base station applications at frequencies from 2500 MHz to 2700 MHz.

Table 1. Typical performance

Typical RF performance at $T_{case} = 25\text{ °C}$ in a common source class-AB production test circuit.

Test signal	f (MHz)	I_{DQ} (mA)	V_{DS} (V)	$P_{L(AV)}$ (W)	G_p (dB)	η_D (%)	ACPR _{5M} (dBc)
2-carrier W-CDMA	2500 to 2700	900	28	25	17	28	-32 [1]

[1] Test signal: 3GPP test model 1; 64 DPCH; PAR = 7.2 dB at 0.01 % probability on CCDF per carrier; 5 MHz carrier spacing.

1.2 Features and benefits

- Excellent ruggedness
- High efficiency
- Low R_{th} providing excellent thermal stability
- Decoupling leads to enable improved video bandwidth
- Designed for broadband operation (2500 MHz to 2700 MHz)
- Lower output capacitance for improved performance in Doherty applications
- Designed for low memory effects providing excellent pre-distortability
- Internally matched for ease of use
- Integrated ESD protection
- Compliant to Directive 2002/95/EC, regarding Restriction of Hazardous Substances (RoHS)

1.3 Applications

- RF power amplifiers for base stations and multi carrier applications in the 2500 MHz to 2700 MHz frequency range



2. Pinning information

Table 2. Pinning

Pin	Description	Simplified outline	Graphic symbol
1	drain		<p>aaa-003619</p>
2	gate		
3	source		
4	decoupling lead		
5	decoupling lead		
6	n.c.		
7	n.c.		

[1] Connected to flange.

3. Ordering information

Table 3. Ordering information

Type number	Package		
	Name	Description	Version
BLF8G27LS-100V	-	earless flanged ceramic package; 6 leads	SOT1244B

4. Limiting values

Table 4. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

Symbol	Parameter	Conditions	Min	Max	Unit
V_{DS}	drain-source voltage		-	65	V
V_{GS}	gate-source voltage		-0.5	+13	V
T_{stg}	storage temperature		-65	+150	°C
T_j	junction temperature		-	225	°C

5. Thermal characteristics

Table 5. Thermal characteristics

Symbol	Parameter	Conditions	Typ	Unit
$R_{th(j-c)}$	thermal resistance from junction to case	$T_{case} = 80\text{ °C}; P_L = 48\text{ W}$	0.292	K/W

6. Characteristics

Table 6. DC characteristics

$T_j = 25\text{ }^\circ\text{C}$ unless otherwise specified.

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
$V_{(BR)DSS}$	drain-source breakdown voltage	$V_{GS} = 0\text{ V}; I_D = 1\text{ mA}$	65	-	-	V
$V_{GS(th)}$	gate-source threshold voltage	$V_{DS} = 10\text{ V}; I_D = 153\text{ mA}$	1.5	1.9	2.3	V
I_{DSS}	drain leakage current	$V_{GS} = 0\text{ V}; V_{DS} = 28\text{ V}$	-	-	4.2	μA
I_{DSX}	drain cut-off current	$V_{GS} = V_{GS(th)} + 3.75\text{ V}; V_{DS} = 10\text{ V}$	-	29	-	A
I_{GSS}	gate leakage current	$V_{GS} = 11\text{ V}; V_{DS} = 0\text{ V}$	-	-	420	nA
g_{fs}	forward transconductance	$V_{DS} = 10\text{ V}; I_D = 153\text{ mA}$	-	1.27	-	S
$R_{DS(on)}$	drain-source on-state resistance	$V_{GS} = V_{GS(th)} + 3.75\text{ V}; I_D = 5.35\text{ A}$	-	0.1	-	Ω

Table 7. RF characteristics

Test signal: 2-carrier W-CDMA, 3GPP test model 1; 64 DPCH; PAR = 7.2 dB at 0.01 % probability on the CCDF; $f_1 = 2502.5\text{ MHz}; f_2 = 2507.5\text{ MHz}; f_3 = 2692.5\text{ MHz}; f_4 = 2697.5\text{ MHz}$; RF performance at $V_{DS} = 28\text{ V}; I_{Dq} = 900\text{ mA}; T_{case} = 25\text{ }^\circ\text{C}$; unless otherwise specified; in a class-AB production test circuit.

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
G_p	power gain	$P_{L(AV)} = 25\text{ W}$	15.8	17	-	dB
η_D	drain efficiency	$P_{L(AV)} = 25\text{ W}$	25	28	-	%
RL_{in}	input return loss	$P_{L(AV)} = 25\text{ W}$	-	-10	-	dB
$ACPR_{5M}$	adjacent channel power ratio (5 MHz)	$P_{L(AV)} = 25\text{ W}$	-	-32	-26	dBc

7. Test information

7.1 Ruggedness in class-AB operation

The BLF8G27LS-100V is capable of withstanding a load mismatch corresponding to $V_{SWR} = 10 : 1$ through all phases under the following conditions: $V_{DS} = 28\text{ V}; I_{Dq} = 900\text{ mA}; P_L = 100\text{ W}; f = 2500\text{ MHz}$.

7.2 Impedance information

Table 8. Typical impedance

Measured load-pull data; $I_{Dq} = 900\text{ mA}$; $V_{DS} = 28\text{ V}$ (main transistor).

f (MHz)	Z_S [1] (Ω)	Z_L [1] (Ω)
2500	1.2 – j4.6	2.7 – j2.7
2600	2.3 – j5.5	2.5 – j2.5
2700	3.8 – j5.2	2.1 – j2.6

[1] Z_S and Z_L defined in [Figure 1](#).

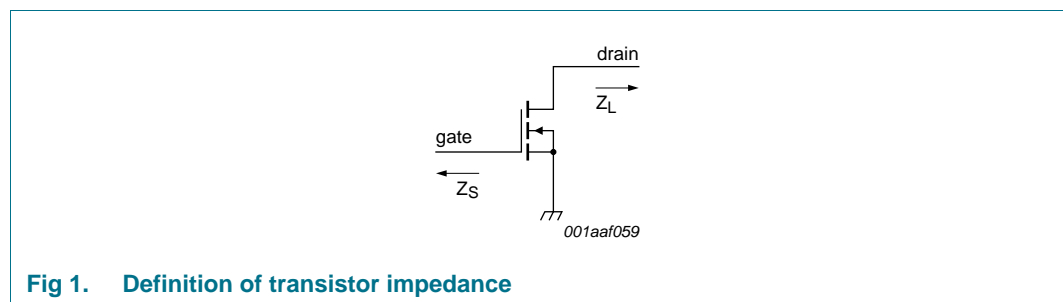


Fig 1. Definition of transistor impedance

7.3 VBW in class-AB operation

The BLF8G27LS-100V shows 110 MHz (typical) video bandwidth in class-AB test circuit in 2.6 GHz band at $V_{DS} = 28\text{ V}$ and $I_{Dq} = 0.9\text{ A}$.

7.4 Test circuit

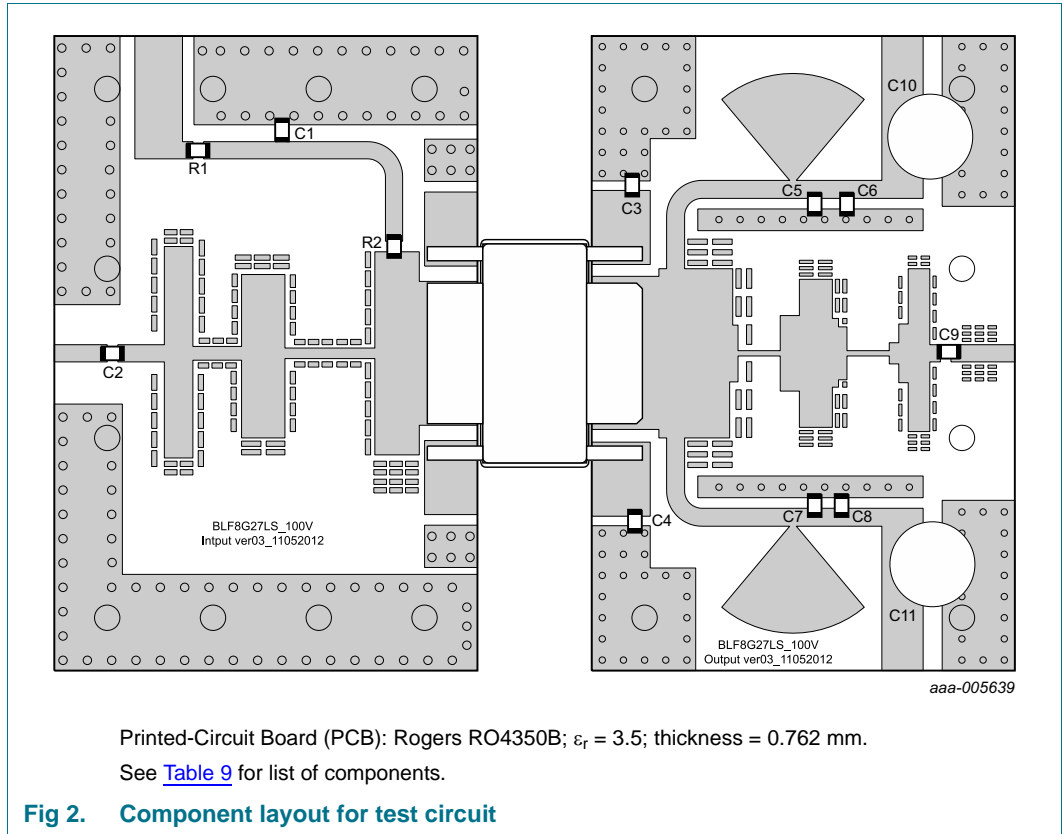


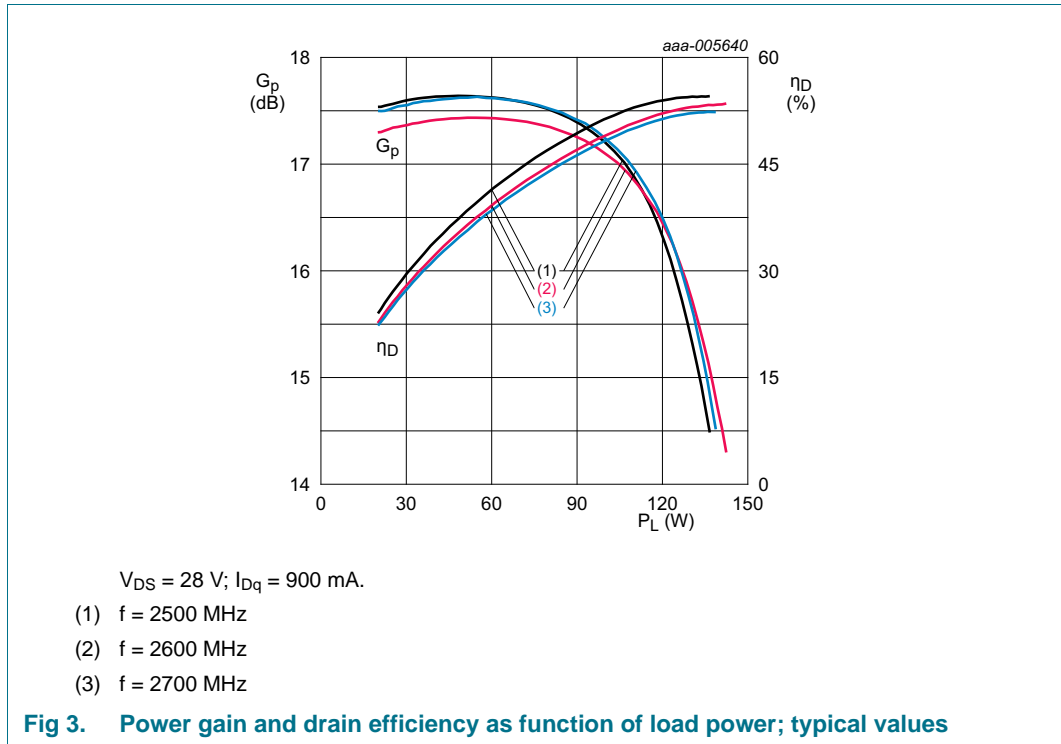
Table 9. List of components

For test circuit, see [Figure 2](#).

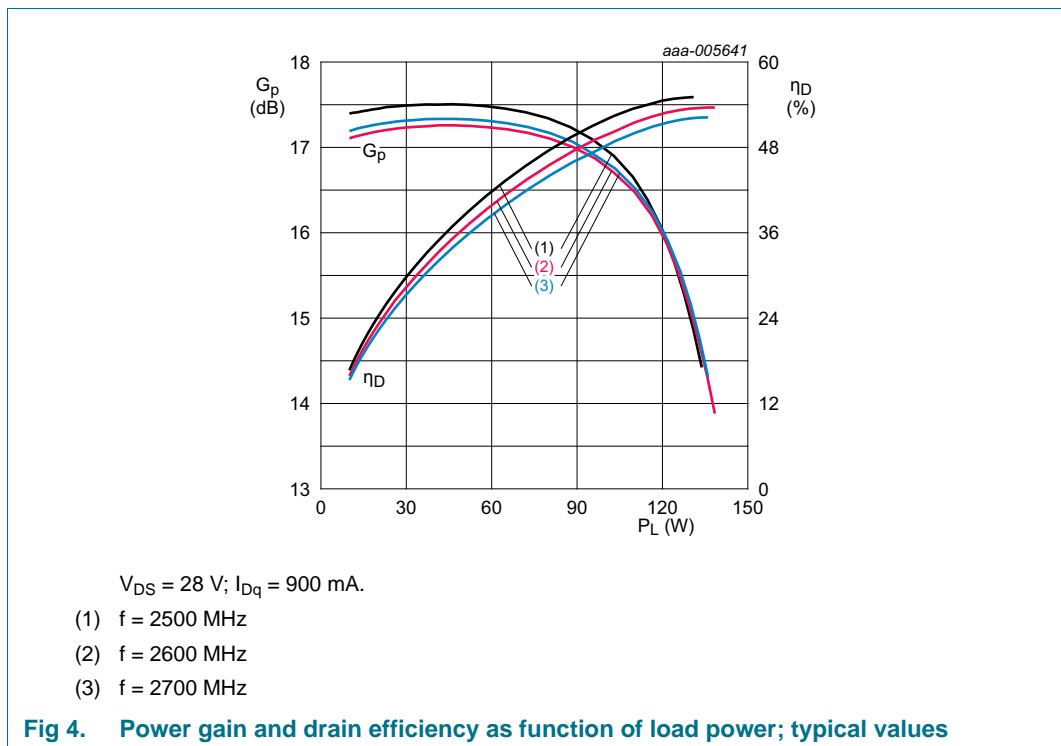
Component	Description	Value	Remarks
C1, C2, C9	multilayer ceramic chip capacitor	20 pF	ATC600F
C3, C4, C6, C8	multilayer ceramic chip capacitor	10 μ F	Murata
C5, C7	multilayer ceramic chip capacitor	0.1 μ F	Murata
C10, C11	electrolytic capacitor	1000 μ F, 100 V	
R1, R2	chip resistor	9.1 Ω	Vishay Dale SMD 0805

7.5 Graphical data

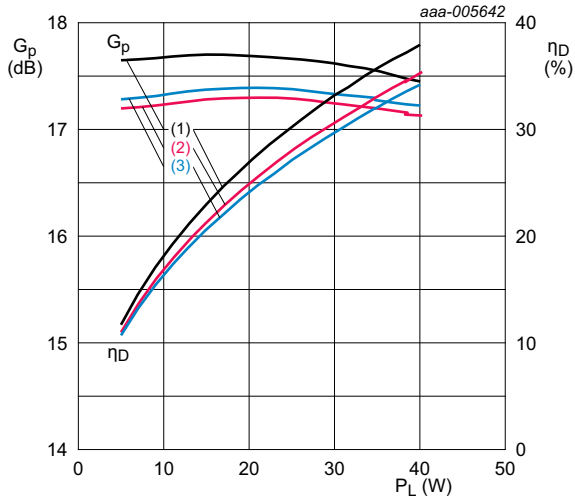
7.5.1 Pulsed CW



7.5.2 1-Tone CW

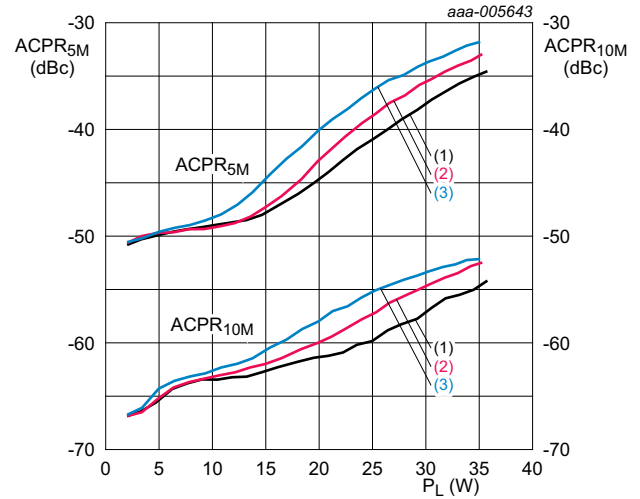


7.5.3 1-Carrier W-CDMA



$V_{DS} = 28\text{ V}; I_{Dq} = 900\text{ mA}$.
 (1) $f = 2500\text{ MHz}$
 (2) $f = 2600\text{ MHz}$
 (3) $f = 2700\text{ MHz}$

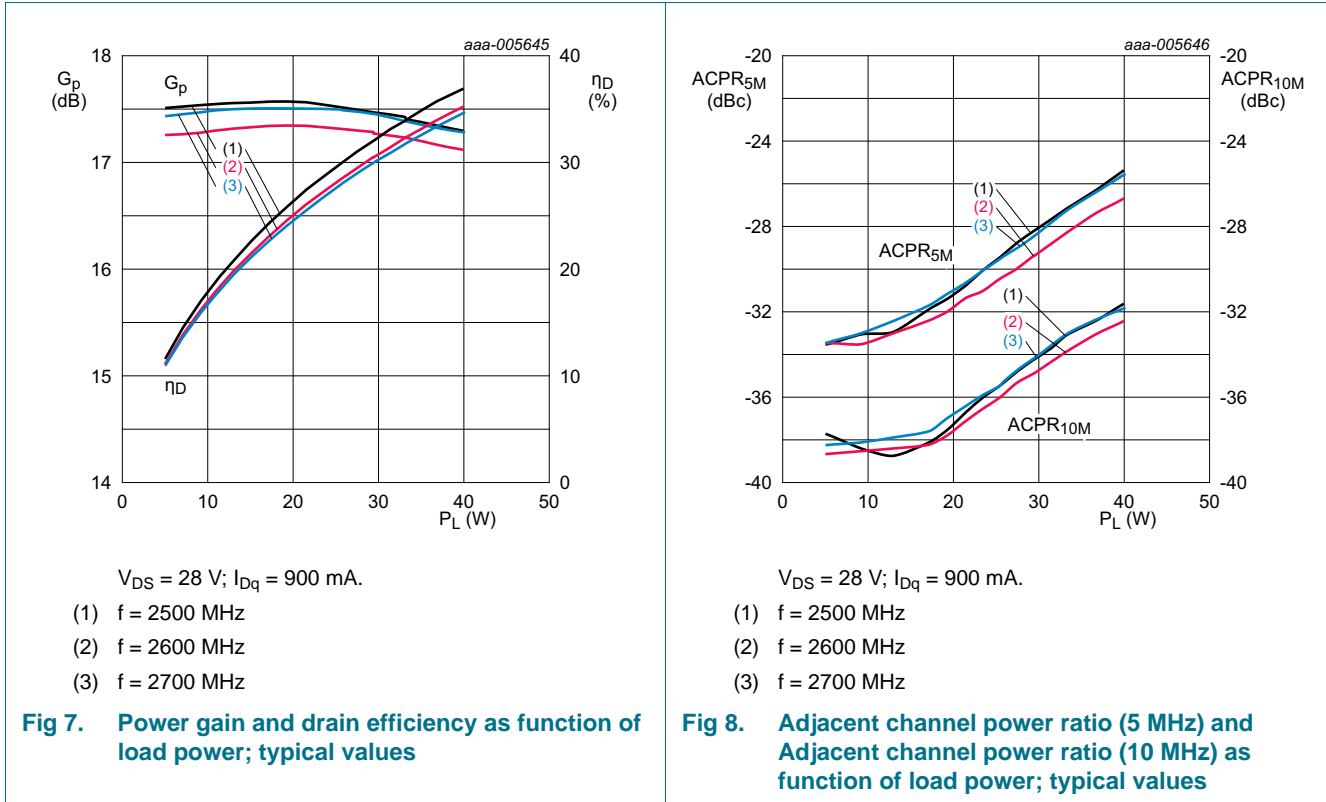
Fig 5. Power gain and drain efficiency as function of load power; typical values



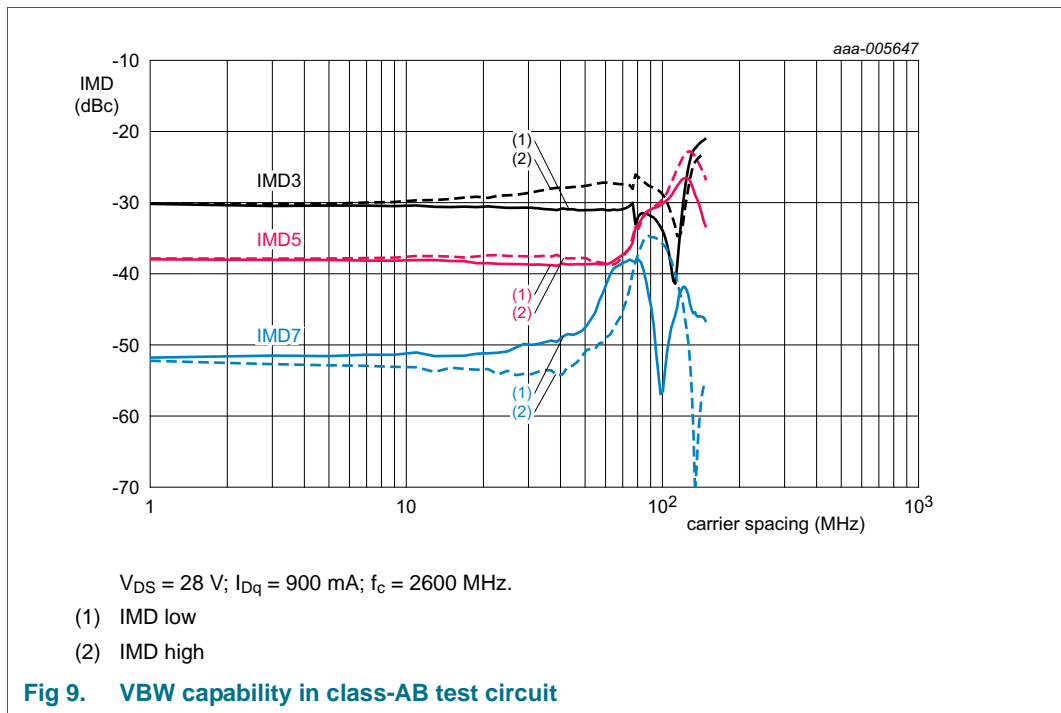
$V_{DS} = 28\text{ V}; I_{Dq} = 900\text{ mA}$.
 (1) $f = 2500\text{ MHz}$
 (2) $f = 2600\text{ MHz}$
 (3) $f = 2700\text{ MHz}$

Fig 6. Adjacent channel power ratio (5 MHz) and Adjacent channel power ratio (10 MHz) as function of load power; typical values

7.5.4 2-Carrier W-CDMA



7.5.5 2-Tone VBW



8. Package outline

Earless flanged ceramic package; 6 leads

SOT1244B

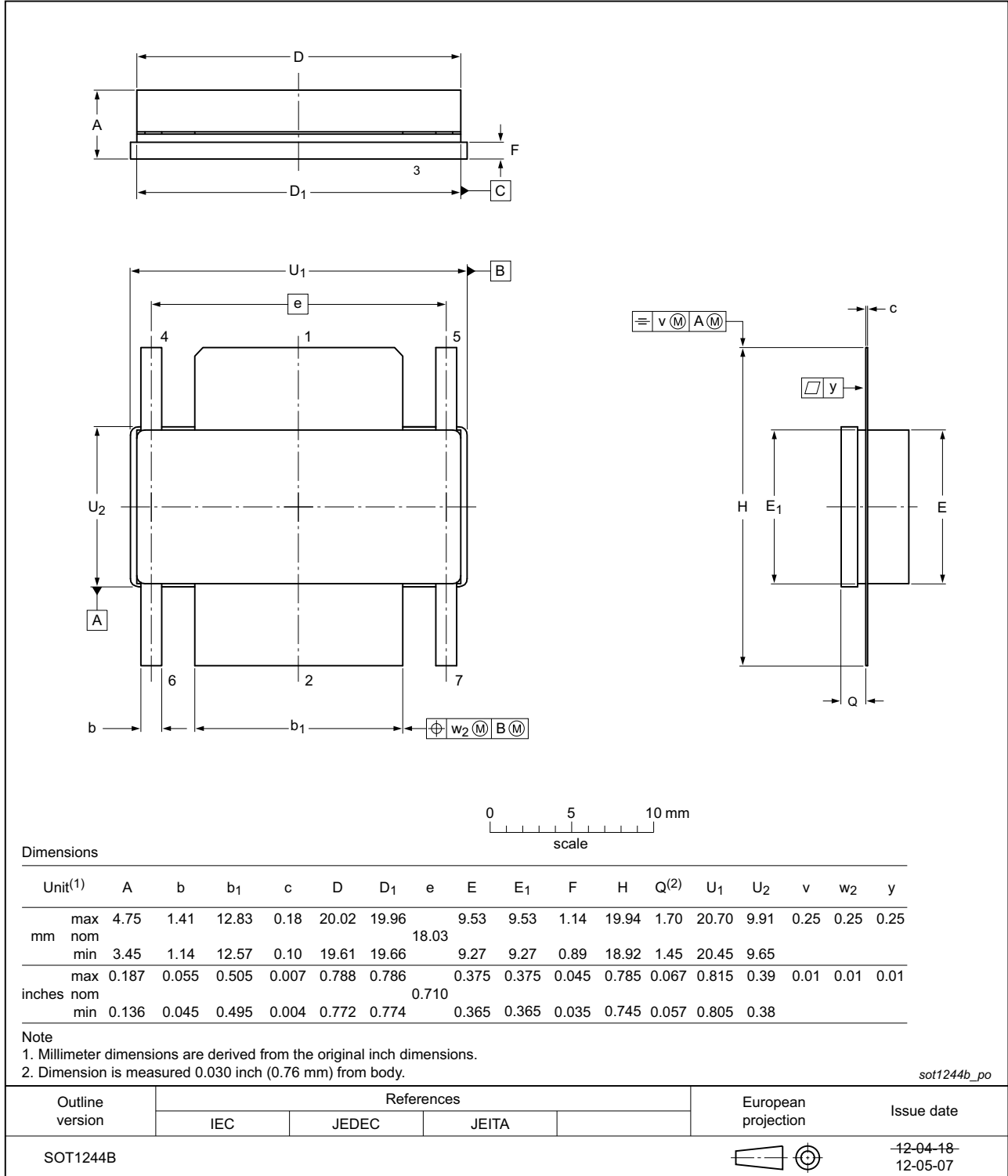


Fig 10. Package outline SOT1244B

9. Handling information

CAUTION



This device is sensitive to ElectroStatic Discharge (ESD). Observe precautions for handling electrostatic sensitive devices.

Such precautions are described in the *ANSI/ESD S20.20*, *IEC/ST 61340-5*, *JESD625-A* or equivalent standards.

10. Abbreviations

Table 10. Abbreviations

Acronym	Description
3GPP	Third Generation Partnership Project
CCDF	Complementary Cumulative Distribution Function
CW	Continuous Wave
DPCH	Dedicated Physical CHannel
ESD	ElectroStatic Discharge
IMD	InterModulation Distortion
LDMOS	Laterally Diffused Metal Oxide Semiconductor
PAR	Peak-to-Average Ratio
SMD	Surface Mounted Device
VBW	Video BandWidth
VSWR	Voltage Standing Wave Ratio
W-CDMA	Wideband Code Division Multiple Access

11. Revision history

Table 11. Revision history

Document ID	Release date	Data sheet status	Change notice	Supersedes
BLF8G27LS-100V v.3	20130129	Product data sheet	-	BLF8G27LS-100V v.2
Modifications:				
			• Figure 6 on page 7 : figure has been updated	
BLF8G27LS-100V v.2	20121203	Product data sheet	-	BLF8G27LS-100V v.1
BLF8G27LS-100V v.1	20120817	Objective data sheet	-	-

12. Legal information

12.1 Data sheet status

Document status ^{[1][2]}	Product status ^[3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
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